

## FUSE CIRCUIT FOR SEMICONDUCTOR INTEGRATED CIRCUIT

### Abstract of the Disclosure

5        In a fuse circuit including programmable fuses in a semiconductor integrated circuit, the fuses store specific information related to the semiconductor integrated circuit, such as redundancy information, wafer lot number, die lot number, and die position on the wafer, etc. While a conventional semiconductor integrated circuit utilizes a single fuse for storing one bit of specific information, the fuse circuit in the present invention utilizes a plurality of fuses for storing identical bit information. Consequently, in the case where a fuse has not been cut out correctly, the fuse circuit of the present invention can reduce programming defects, whereby defect generation rates are remarkably decreased.

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